SN54LS55, SN74LS55
2-WIDE 4-INPUT AND-OR-INVERT GATES

SDLS181

DECEMBER 1983—REVISED MARCH 1988

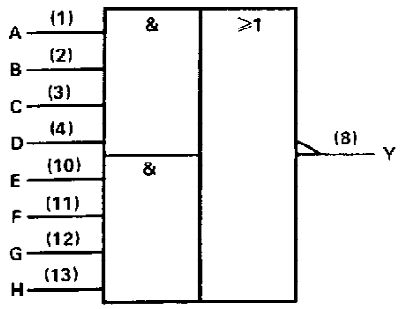
- **Package Options Include "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs**
- **Dependable Texas Instruments Quality and Reliability**

description

These devices contain 2-wide 4-input AND-OR-INVERT gates. They perform the Boolean function $Y = \overline{ABCD + EFGH}$.

The SN54LS55 is characterized for operation over the full military temperature range of −55°C to 125°C. The SN74LS55 is characterized for operation from 0°C to 70°C.

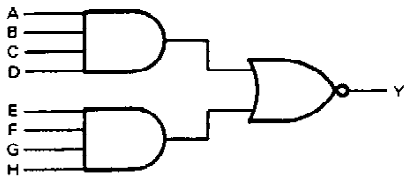
logic symbol†



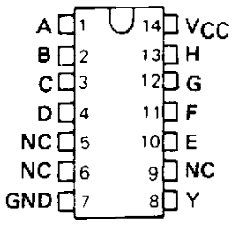
positive logic: $Y = \overline{ABCD + EFGH}$

†This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.
Pin numbers shown are for D, J, N, and W packages.

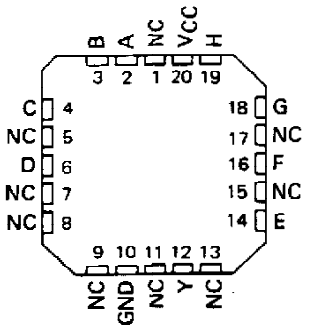
logic diagram



SN54LS55 . . . J OR W PACKAGE
SN74LS55 . . . D OR N PACKAGE
(TOP VIEW)

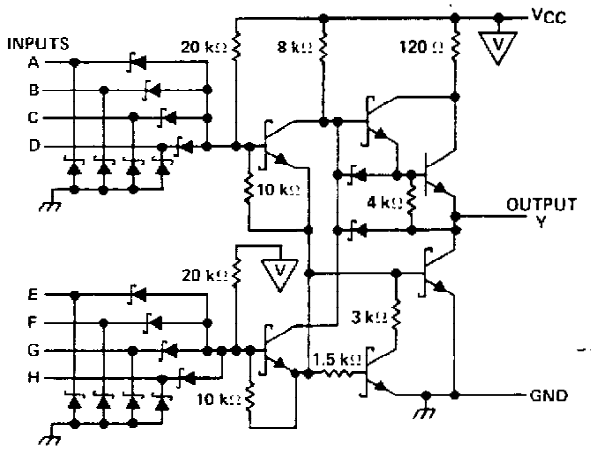


SN54LS55 . . . FK PACKAGE
(TOP VIEW)



NC - No internal connection

schematic



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 7 V
Operating free-air temperature: SN54LS55 . . . . . −55°C to 125°C
SN74LS55 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	SN54LS55			SN74LS55			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{IH} High-level input voltage	2			2			V
V_{IL} Low-level input voltage			0.7			0.8	V
I_{OH} High-level output current			−0.4			−0.4	mA
I_{OL} Low-level output current			4			8	mA
T_A Operating free-air temperature	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS†			SN54LS55			SN74LS55			UNIT
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}	V_{CC} = MIN,	I_I = −18 mA				−1.5			−1.5	V
V_{OH}	V_{CC} = MIN,	V_{IL} = MAX,	I_{OH} = −0.4 mA	2.5	3.4		2.7	3.4		V
V_{OL}	V_{CC} = MIN,	V_{IH} = 2 V,	I_{OL} = 4 mA		0.25	0.4		0.25	0.4	V
	V_{CC} = MIN,	V_{IH} = 2 V,	I_{OL} = 8 mA					0.35	0.5	
I_I	V_{CC} = MAX,	V_I = 7 V				0.1			0.1	mA
I_{IH}	V_{CC} = MAX,	V_I = 2.7 V				20			20	μA
I_{IL}	V_{CC} = MAX,	V_I = 0.4 V				−0.4			−0.4	mA
I_{OS}§	V_{CC} = MAX			−20		−100	−20		−100	mA
I_{CCH}	V_{CC} = MAX,	V_I = 0 V			0.4	0.8		0.4	0.8	mA
I_{CCL}	V_{CC} = MAX,	See Note 2			0.7	1.3		0.7	1.3	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.
NOTE 2: All outputs of one AND gate at 4.5 V, all others at GND.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Any	Y	R_L = 2 kΩ,	C_L = 15 pF		12	20	ns
t_{PHL}						12.5	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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